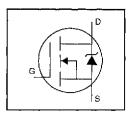
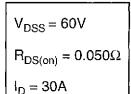


## HEXFET® Power MOSFET

- Dynamic dv/dt Rating
- · Logic-Level Gate Drive
- RDS(on) Specified at VGS=4V & 5V
- 175°C Operating Temperature
- Fast Switching
- Ease of Paralleling
- · Simple Drive Requirements

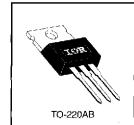




### Description

Third Generation HEXFETs from International Rectifier provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



#### **Absolute Maximum Ratings**

	Parameter	Max.	Units
ID @ TC = 25°C	Continuous Drain Current, VGS @ 5.0 V	30	Ī
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 5.0 V	21	- A
IDM	Pulsed Drain Current ①	110	
P <sub>D</sub> @ T <sub>C</sub> = 25°C	Power Dissipation	88	W
	Linear Derating Factor	0.59	W/°C
V <sub>G</sub> s	Gate-to-Source Voltage	±10	
Eas	Single Pulse Avalanche Energy ②	220	mJ
dv/dt	Peak Diode Recovery dv/dt ③	4.5	V/ns
TJ	Operating Junction and	-55 to +175	T
T <sub>STG</sub>	Storage Temperature Range		∘c
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting Torque, 6-32 or M3 screw	10 lbf•in (1.1 N•m)	

#### Thermal Resistance

	Parameter	Min.	Тур.	Мах.	Units
Reuc	Junction-to-Case	_		1.7	
Recs	Case-to-Sink, Flat, Greased Surface	_	0.50		°C/W
Reja	Junction-to-Ambient	-	_	62	

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# Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Test Conditions	
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	60			V	V <sub>GS</sub> =0V, I <sub>D</sub> = 250μA	
AV(BR)DSS/AT,	Breakdown Voltage Temp. Coefficient	_	0.070	_	V/°C	Reference to 25°C, ID= 1mA	
	Static Drain-to-Source On-Resistance			0.050	Ω	V <sub>GS</sub> =5.0V, I <sub>D</sub> =18A @	
Ros(on)	Static Drain-to-Source Off-nesistance	_		0.070	27	V <sub>GS</sub> =4.0V, l <sub>D</sub> =15A ④	
V <sub>GS(th)</sub>	Gate Threshold Voltage	. 1.0	—	2.0	٧	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> = 250μA	
9ts	Forward Transconductance	12	_	_	S	V <sub>DS</sub> =25V, I <sub>D</sub> =18A ④	
	Drain-to-Source Leakage Current		_	25	μΑ	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V	
IDSS	Drain-to-Source Leakage Current	_	<u> </u>	250	μА	V <sub>DS</sub> =48V, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C	
	Gate-to-Source Forward Leakage		_	. 100	nΑ	V <sub>GG</sub> =10V	
less	Gate-to-Source Reverse Leakage	_	_	-100	на	V <sub>GS</sub> =-10V	
Qg	Total Gate Charge		_	35		I <sub>D</sub> =30A	
Qgs	Gate-to-Source Charge		_	7.1	пC	V <sub>DS</sub> =48V	
Qgd	Gate-to-Drain ("Miller") Charge	_	_	25		V <sub>GS</sub> =5.0V See Fig. 6 and 13 €	
t <sub>d(on)</sub>	Turn-On Delay Time	_	14			V <sub>DD</sub> =30V	
tr	Rise Time	_	170	<u> </u>	ns	I <sub>D</sub> =30A	
t <sub>d(off)</sub>	Turn-Off Delay Time		30	<u> </u>	110	R <sub>G</sub> =6.0Ω	
t <sub>f</sub>	Fall Time		56	<u> </u>		R <sub>D</sub> =1.0Ω See Figure 10 €	
L <sub>D</sub>	Internal Drain Inductance	_	4.5	· _	nН	Between lead, 6 mm (0.25in.)	
Ls	Internal Source Inductance		7.5	_	1111	from package and center of die contact	
Ciss	Input Capacitance	_	1600	_		V <sub>GS</sub> =0V	
Coss	Output Capacitance	<u> </u>	660	_	pF	V <sub>DS</sub> =25V	
Cras	Reverse Transfer Capacitance		170	_		f=1.0MHz See Figure 5	

## Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Test Conditions
Is	Continuous Source Current (Body Diode)		_	30	Α	MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①		_	110	] ^	integral reverse e p-n junction diode.
Vsb	Diode Forward Voltage	_	_	1.6	٧	T_=25°C, Is=30A, VGS=0V @
trr	Reverse Recovery Time		120	180	ns	TJ=25°C, IF=30A
Qrr	Reverse Recovery Charge		0.70	1.3	μC	di/dt=100A/μs ②
ton	Forward Turn-On Time	Intrinsic turn-on time is neglegible (turn-on is dominated by Ls+Lp)				

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature (See Figure 11)
- ③ Isp≤30A, di/dt≤200A/μs, Vpp≤V(BR)Dss, TJ≤175°C
- ② V<sub>DD</sub>=25V, starting T<sub>J</sub>=25°C, L=285μH  $R_{G}=25\Omega$ , I<sub>AS</sub>=30A (See Figure 12)
- 3 Pulse width ≤ 300 μs; duty cycle ≤2%.

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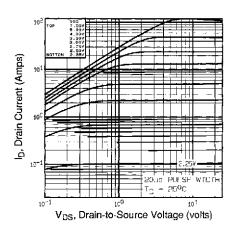


Fig 1. Typical Output Characteristics, Tc=25°C

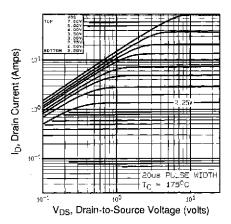


Fig 2. Typical Output Characteristics, T<sub>C</sub>=175°C

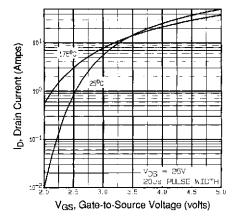
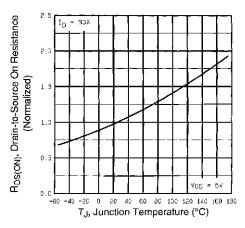


Fig 3. Typical Transfer Characteristics



**Fig 4.** Normalized On-Resistance Vs. Temperature

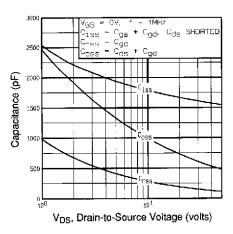


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

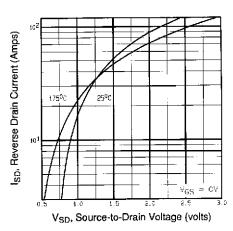


Fig 7. Typical Source-Drain Diode Forward Voltage

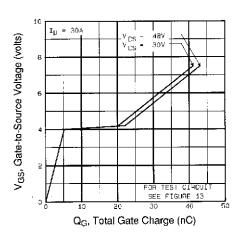


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

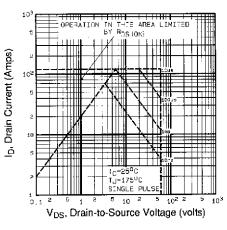


Fig 8. Maximum Safe Operating Area

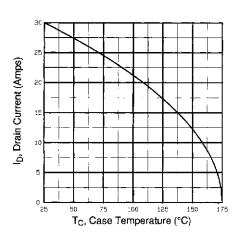


Fig 9. Maximum Drain Current Vs. Case Temperature

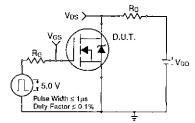


Fig 10a. Switching Time Test Circuit

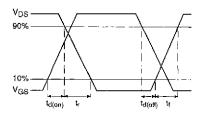


Fig 10b. Switching Time Waveforms

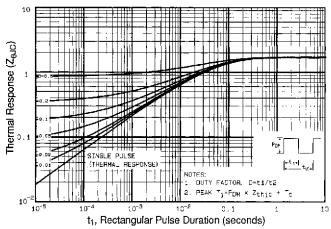


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

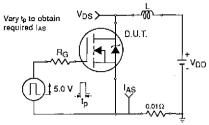


Fig 12a. Unclamped Inductive Test Circuit

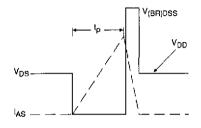


Fig 12b. Unclamped Inductive Waveforms

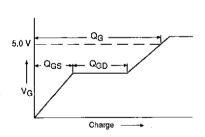


Fig 13a. Basic Gate Charge Waveform

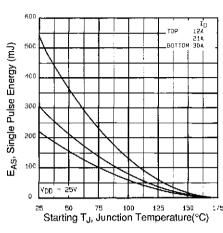


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

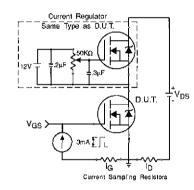


Fig 13b. Gate Charge Test Circuit

Appendix A: Figure 14, Peak Diode Recovery dv/dt Test Circuit - See page 1505

Appendix B: Package Outline Mechanical Drawing - See page 1509

Appendix C: Part Marking Information - See page 1516

Appendix E: Optional Leadforms - See page 1525





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